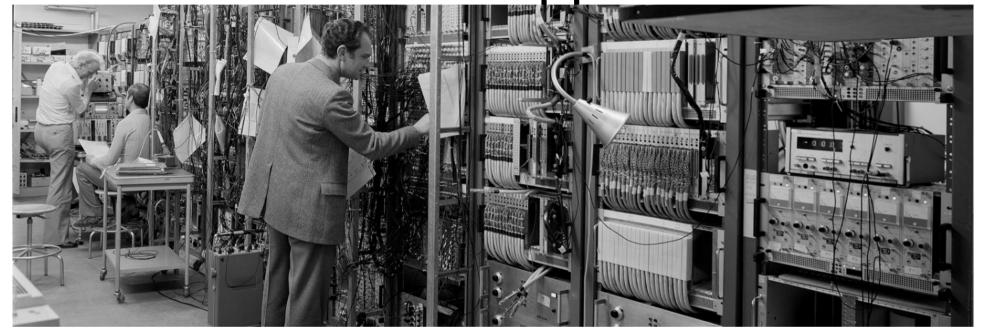


# DAQ HW



# Hands-on Approach





#### **ISOTDAQ 2022**

**12<sup>th</sup> International School of Trigger and Data Acquisition** 13-23 June 2022

INFN Sez. Catania & Department of Physics and Astronomy "E.Majorana", Catania

Catania, 14 Jun 2022

vincenzo.izzo@cern.ch

- This wants to be a hands-on approach to the basic DAQ hardware
  - We will discuss different experiments, requiring different techniques and components
  - We also have some good real data to discuss
  - You will see, we are talking about real life here

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    Where

    How do physics events become bits and numbers?

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- Acknowledgements
  - © Andrea Negri (Univ. of Pavia, Italy)
  - © Wainer Vandelli (CERN/PH-ATD)
  - © Sergio Ballestrero (Univ. Johannesburg & CERN)
    - Material and ideas have been taken from CERN Summer Student lectures of P.Farthouat, C.Joram and O.Ullaland; the "Physics data acquisition and analysis" lessons given by R.Ferrari at the University of Parma, Italy, "Analog and Digital Electronics for Detectors" of H. Spieler and all lectures of ISOTDAQ schools, in particular M.Joos and C.Schwick

### Introduction on DAQ

From previous lecture (A. Negri)

- → "Data Acquisition" on Wikipedia: data acquisition (DAQ) is the process of **sampling signals** that measure real world physical conditions and **converting** the resulting samples into digital numeric values that....
- →Data acquisition is an **alchemy** of electronics, computer science, networking, physics
- .... resources and manpower matter as well, ...

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- .... resources and manpower matter as well, ...

- →DAQ is a wide and vast field
  - →I will mostly refer to DAQ in High-Energy Physics
    - →We'll discuss only the basic principles of DAQ
      - → Some of these might be the starting points for your next experiments

#### **Electronics: What is needed for?**

Typically, electronics interfaces DAQ with the detector

→Collect electrical signals from the detector. Usually a short current pulse

#### **Electronics: What is needed for?**

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- →Collect electrical signals from the detector. Usually a short current pulse
- → Acquire & Shape the signal to optimize different, incompatible, characteristics
- → Compromise
  - Detect minimum detectable signal
  - Precise energy measurement
  - Fast signal rate
  - Precise timing
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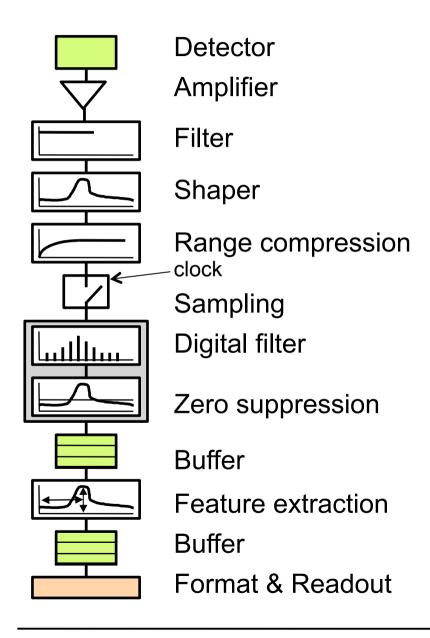
→ Acquire & Shape the signal to optimize different, **incompatible**, characteristics → Compromise

- Detect minimum detectable signal
- Precise energy measurement
- Fast signal rate
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- Insensitivity to pulse shape

#### →Digitize the signal

- provide a digital representation of the measurement
- allow for subsequent processing, transmission, storage using digital electronics → Computers, Fibres, Networks, ...

#### Readout chain



#### → Front-end electronics very specialized

- translates signals from a specific detector to a standard digital world
- custom build to match detector characteristics

## →We cannot discuss all design and architecture details

 if you are into electronic design you already know many topics

#### → I want to provide you with basic guidelines

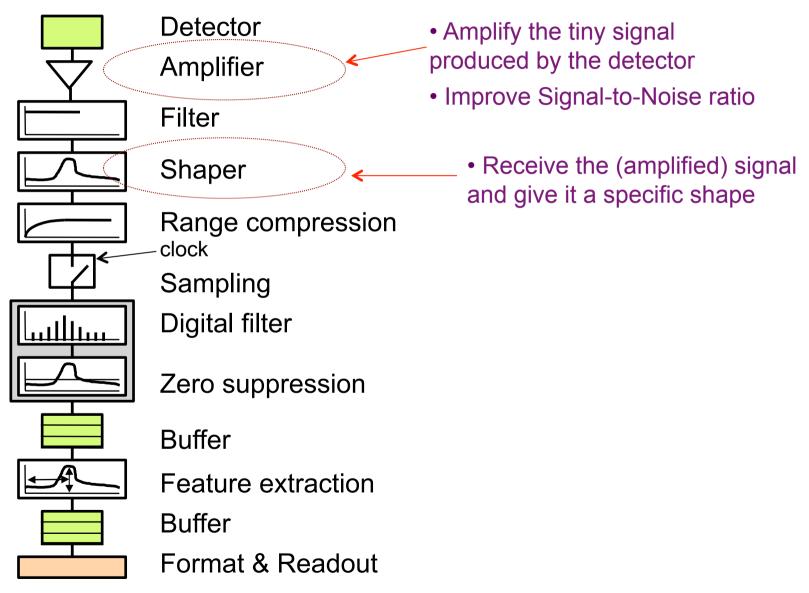
 This hopefully may help you when dealing or choosing commercial electronics

→We only discuss selected functions and principles

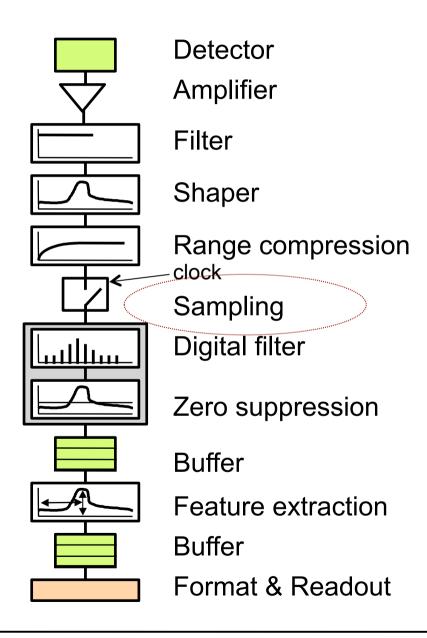
#### Readout chain

#### Main functionalities:

14



### Readout chain

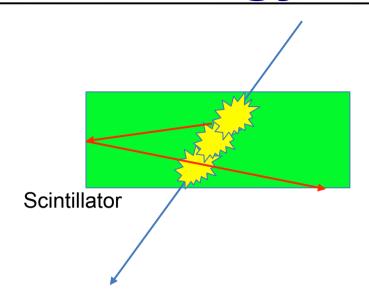


#### **Outline**

- Introduction
  - DAQ, Electronics & Readout Chain
- Measure energy deposition
  - Scintillator setup
  - Photomultiplier
  - Analog-to-Digital conversion
  - Charge-to-Digital conversion
  - QDC in real life
- Measure position
  - Wire chamber setup
  - Time-to-Digital conversion
  - TDC in real life
- Corollary



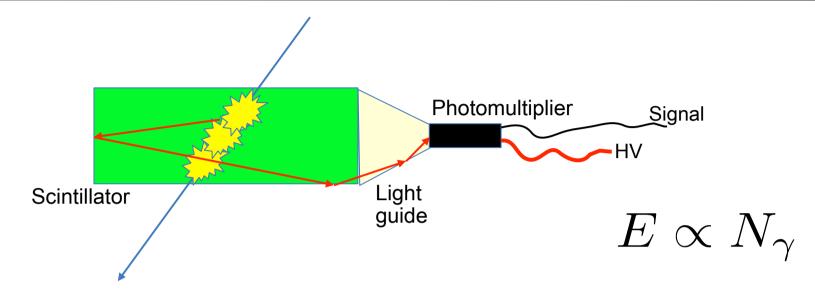
## **Energy measurement**



$$E \propto N_{\gamma}$$

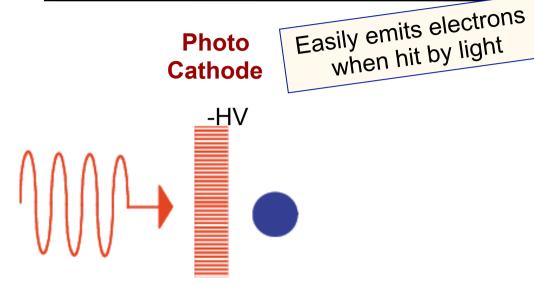
- Measure energy deposited by a particle traversing a medium
- The medium (detector) is a **scintillator** 
  - Molecules, excited by the passing particle, relax emitting light
  - The amount of light is <u>proportional</u> to the deposited energy
  - We want to collect light with the highest possible collection efficiency

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  - We want to collect light with the highest possible collection efficiency
- The light is then
  - collected, using dedicated passive optical means (light guide)
  - fed into a photo-detector: **photomultiplier**

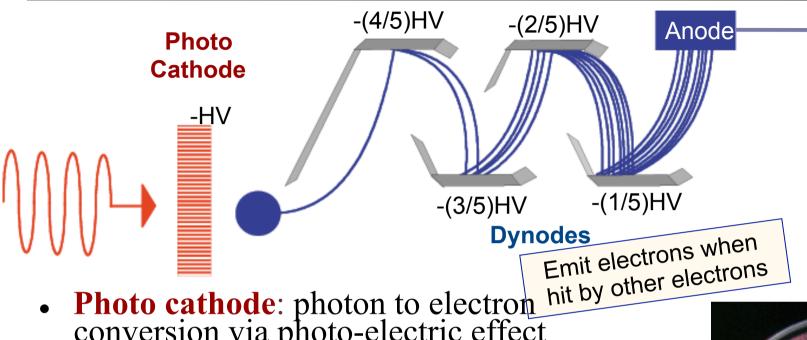
## Photomultiplier



- **Photo cathode**: photon to electron conversion via photo-electric effect
  - typical quantum efficiency ≈1-10% (max 30%), depends on material and wavelength



## **Photomultiplier**



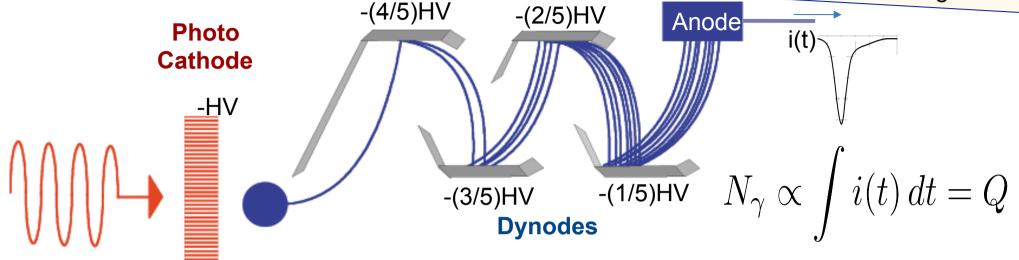
conversion via photo-electric effect

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- **Dynodes**: electrodes that amplify number of electrons thanks to secondary emission
  - Photocathode to anode: typical overall gain  $\approx 10^6$



## **Photomultiplier**

Very few photons converted into an electrical signal



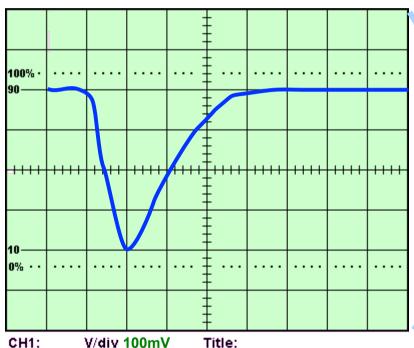
- **Photo cathode**: photon to electron conversion via photo-electric effect
  - typical quantum efficiency ≈1-10% (max 30%), depends on material and wavelength
- **Dynodes**: electrodes that amplify number of electrons thanks to secondary emission
  - Photocathode to anode: typical overall gain  $\approx 10^6$
- Dark current: noise
  - current flowing in PMT without light, due to thermal fluctuations



## Start the measurement

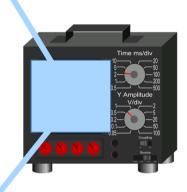
• Approximate Q measurement using oscilloscope

- Linear approximation of a exponential decay



CH1: V/div 100mV Ti CH2: V/div

Time/div: 20ns



V(t)  $R=50\Omega$ 

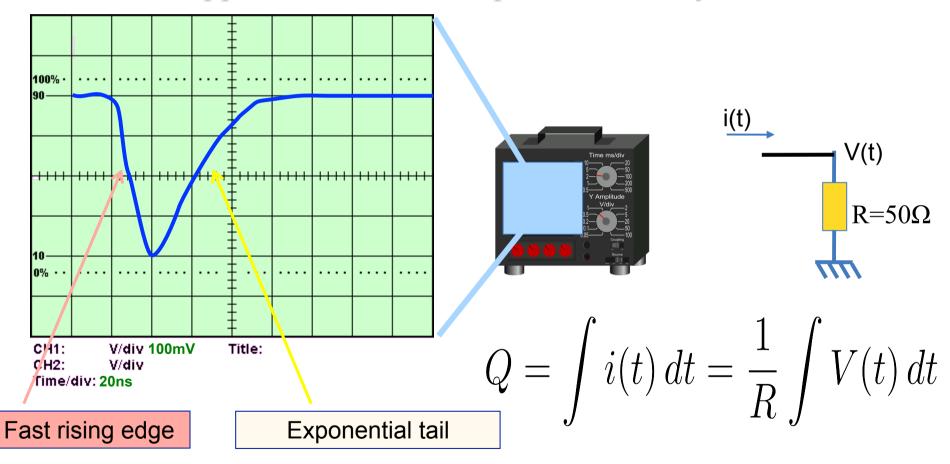
We start from an electron pulse, i.e. a current signal

$$Q = \int i(t) dt = \frac{1}{R} \int V(t) dt$$

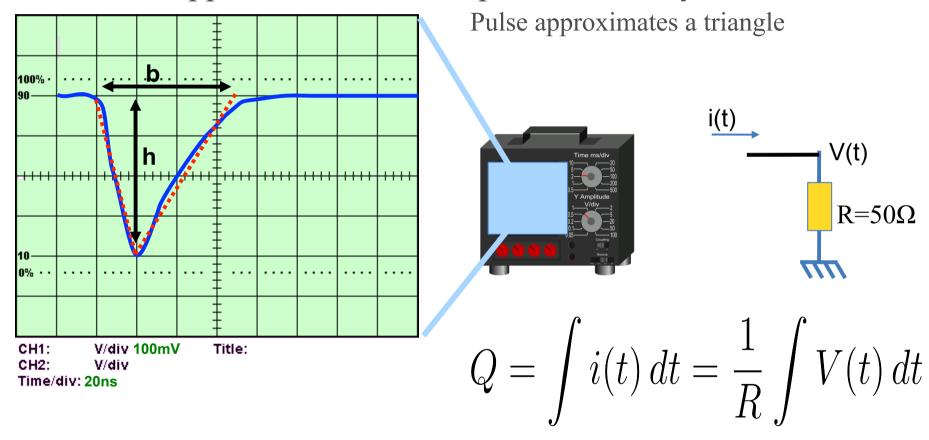
Remeber: the TOTAL charge is proportional to the light

### Start the measurement

- Approximate Q measurement using oscilloscope
  - Linear approximation of a exponential decay

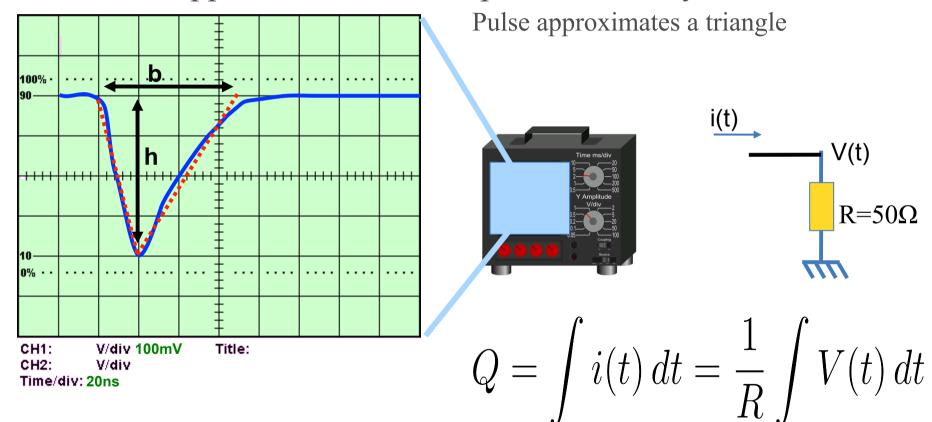


- Approximate Q measurement using oscilloscope
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$$Q pprox rac{1}{R} rac{bh}{2} = rac{1}{50\Omega} rac{(3.5 \cdot (20 ext{ns}))(4 \cdot (100 ext{mV}))}{2} = 280 ext{pC}$$

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  - Linear approximation of a exponential decay
- We have a number representing our event! It's easy, but
  - Deadtime 3 5 min,  $\sim 3 \times 10^{-3}$  Hz (if you are good)
  - Necessary to encode data into some sort of electronic format by hand, in order to manipulate it, visualize it, etc..

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- It would be much more convenient to have a direct electronic measurement
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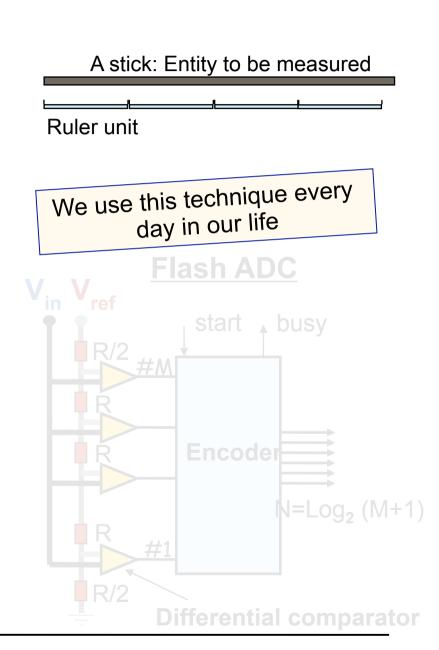
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LHC experiments have millions of channels to be acquired @40 MHz

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- It would be much more convenient to have a direct electronic measurement
  - Save data in some digital format, fill a histogram on-line, etc ...
- N.B.: the oscilloscope method is still fundamental
  - it allows for the **validation** of your DAQ
  - yes, you should never thrust it a priori!



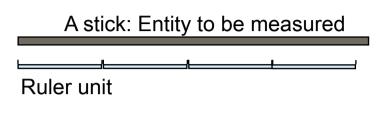
- Digitization
- \_\_\_\_Lab 8
- Encoding an analog value into a binary representation
- By comparing entity with a ruler
- Flash ADC simplest and fastest implementation
  - M comparisons in parallel
  - Input voltage V<sub>in</sub> compared with M fractions of a reference voltage
    - $(1/2) \mathbf{V}_{ref}/\mathbf{M} \rightarrow (M-1/2) \mathbf{V}_{ref}/\mathbf{M}$
    - E.g.: M=3
  - Result is encoded into a compact binary form of N bits
    - $N=Log_2(M+1)$



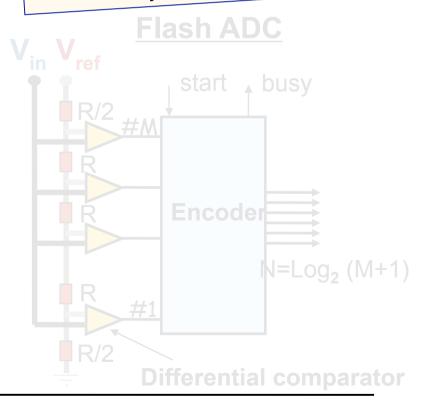
- Digitization
  - Encoding an analog value into a binary representation

Lab 8

- By comparing entity with a ruler
- Flash ADC simplest and fastest implementation
  - Now our entity is a voltage, and we need one (or more) voltage as a reference
    - (1/2)  $V_{ref}/NI \rightarrow (M-1/2)$   $V_{ref}/NI$
    - E.g.: M=3
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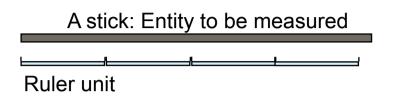


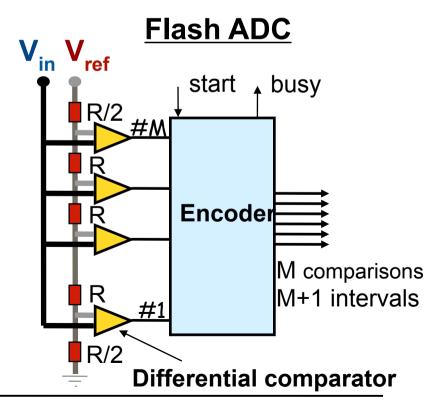
We use this technique every day in our life



#### • Digitization

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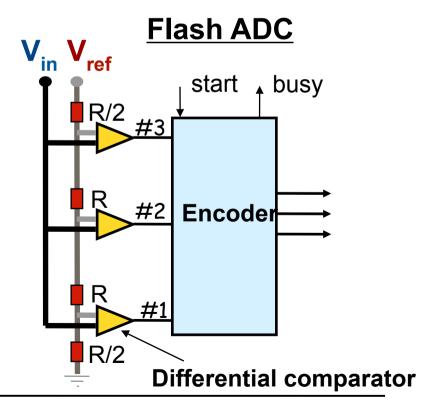




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$x = V_{in}/V_{ref}$	Comparison results	
x <1/6	000	
1/6≤ x <3/6	001	
3/6≤ x <5/6	011	
5/6≤ x	111	

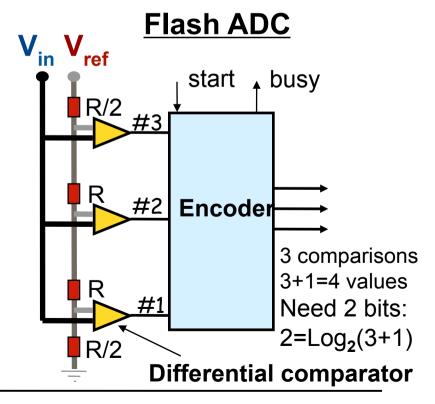


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    - Example: M=3 comparisons
  - $V_{in}/V_{ref}$  takes one of M+1 values.

N-bit Result is encoded in compact binary ADC form of N bits, N=Log<sub>2</sub> (M+1) bits

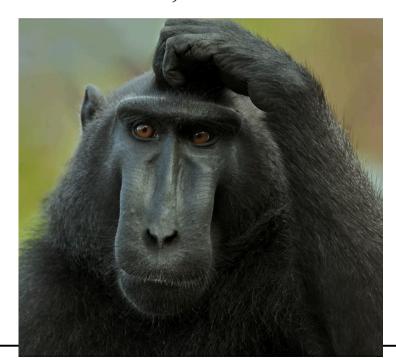
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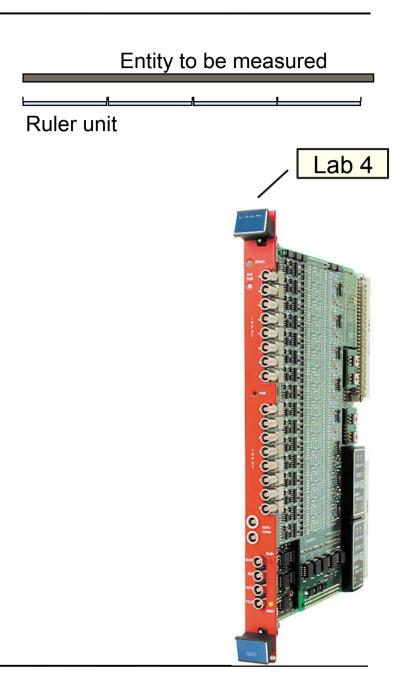


### **ADC Characteristics**

• We want to buy the ADC that best fits with our needs:

• We want a very fast device, with very low power consumption, with less than 1 mV resolution, etc..



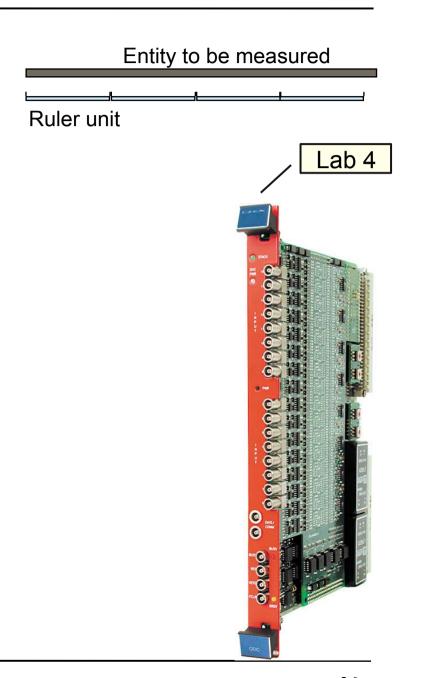


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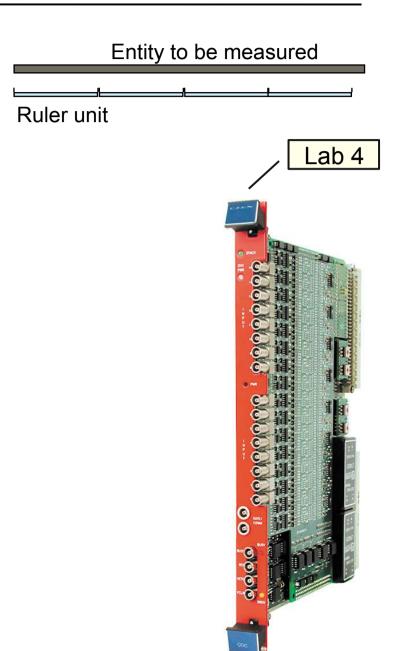


Vincenzo Izzo

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- Resolution (LSB), the ruler unit:  $V_{\text{max}}/2^{N}$ 
  - e.g.: 1V and 8bit (M=256)  $\rightarrow$  LSB = 3.9 mV

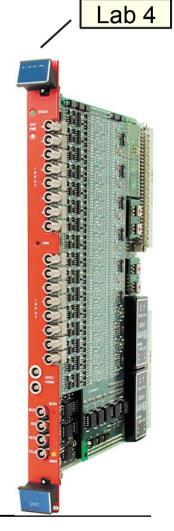
Entity to be measured

Ruler unit

• Quantization error: ±LSB/2

Resolution depends on the number of comparators in the ADC

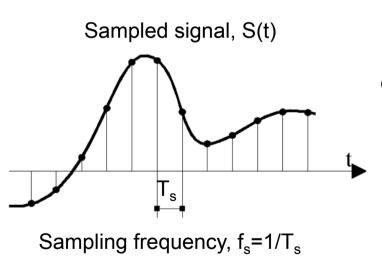
The N (number of bits) essentially tells you how many steps you have in the ADC

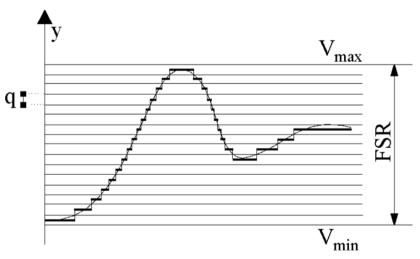


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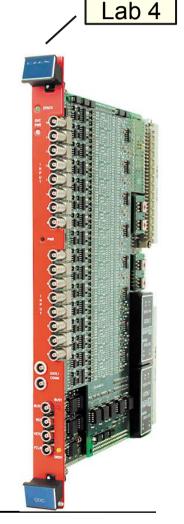
Entity to be measured
Ruler unit

• Quantization error: ±LSB/2





Amplitude coding with N=4 (16 different steps)

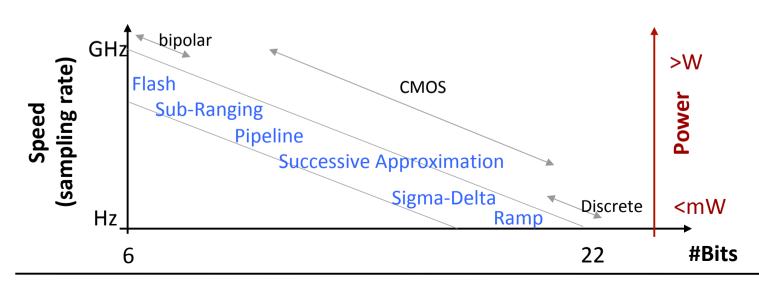


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Entity to be measured
Ruler unit

• Quantization error: ±LSB/2

- Many different ADC architecture/technique exists
  - mostly because of the trade-off between speed and resolution

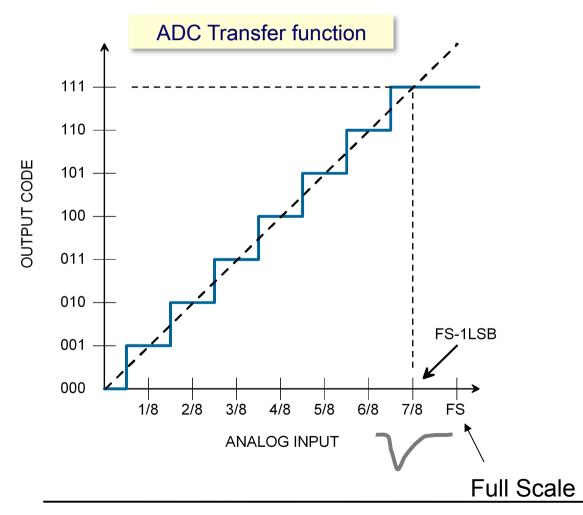




Lab 4

## **ADC Accuracies**

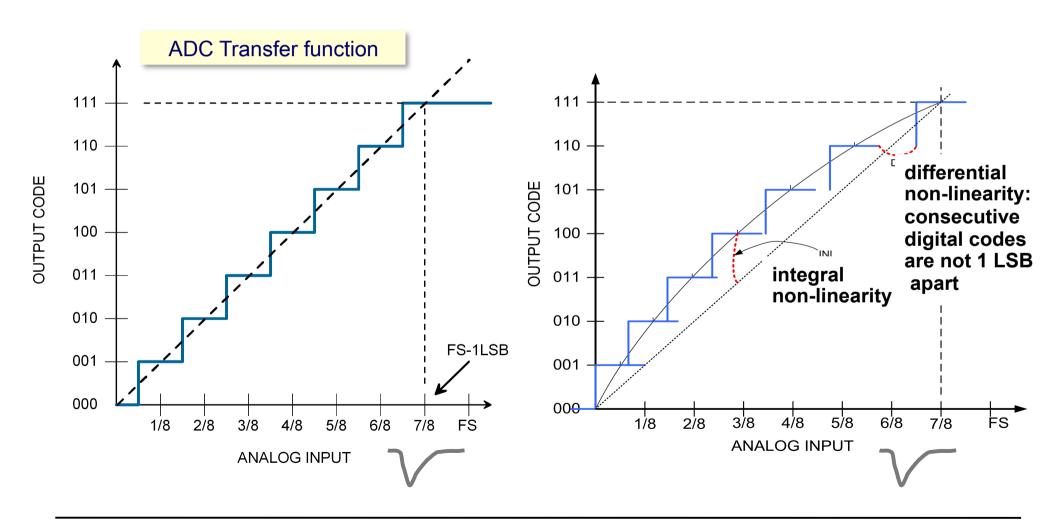
- ADC transfer function
  - Output code vs analog input



# ADC (In)Accuracies

#### • ADC transfer function

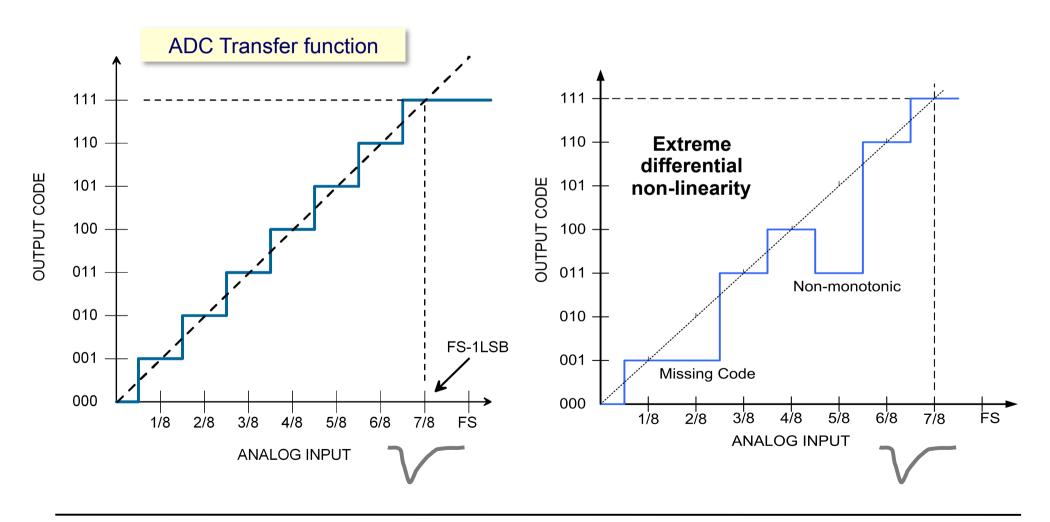
- Output code vs analog input



# ADC (In)Accuracies

#### • ADC transfer function

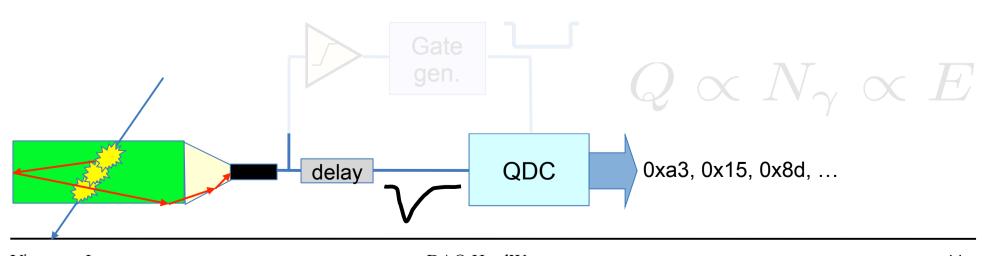
- Output code vs analog input



# **Charge to Digital**

- ADC converts a voltage into a digital representation
  - However, in our experiment, we have a current and we are interested in the total charge
- We need a QDC (Charge to Digital Converter)
  - Essentially an integration step followed by an ADC
  - Integration requires limits → gate

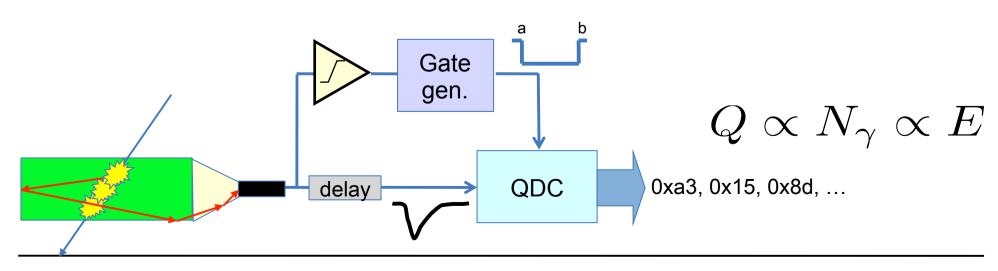
$$I = \int_{a}^{b} f(x) \, dx$$



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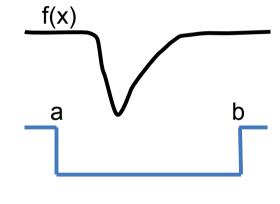


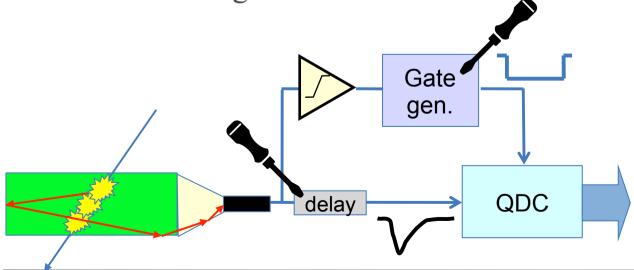
# QDC: timing

- Relative timing between <u>signal</u> and <u>gate</u> is important
  - Delay tuning

Labs 2, 3, 4

- Gate should be **large enough** to contain the full pulse and to accommodate for the jitter
  - Fluctuations are always with us!
- Gate should **not** be **too large** 
  - Increases the noise level
  - By the way, which is the noise contribution to our charge measurement?





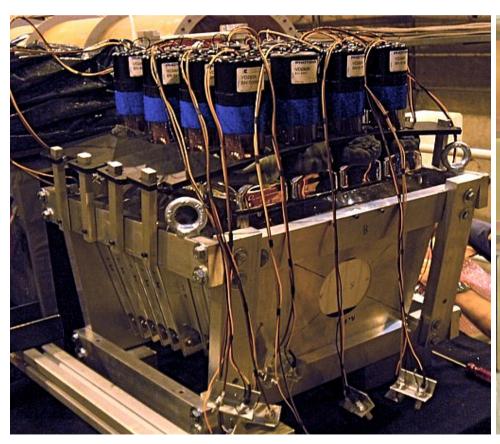
$$Q \propto N_{\gamma} \propto E$$

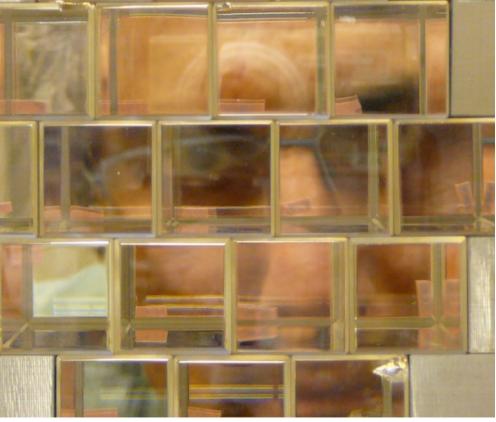
0xa3, 0x15, 0x8d, ...

# **Example of QDC data**

• Calorimetry R&D test beam @CERN







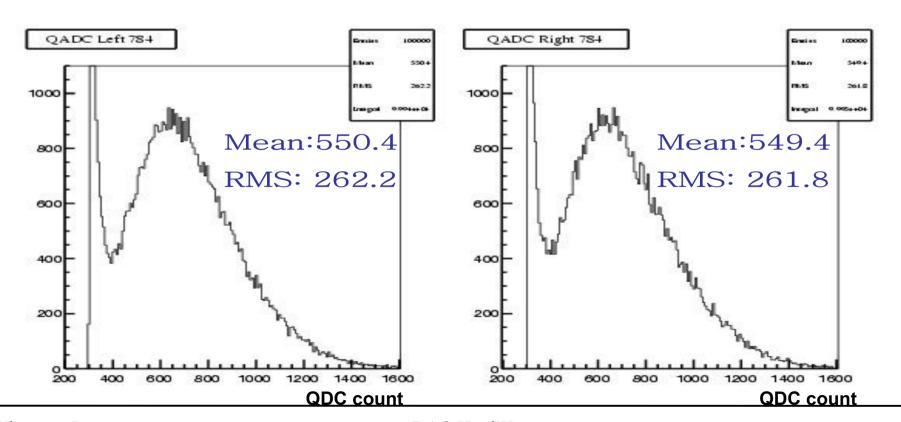
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# QDC spectra

- Calorimetry R&D test beam @CERN
  - QDC spectra

$$Q \propto N_{\gamma} \propto E$$

- But, what is the 1<sup>st</sup> peak?
  - How can we estimate it?

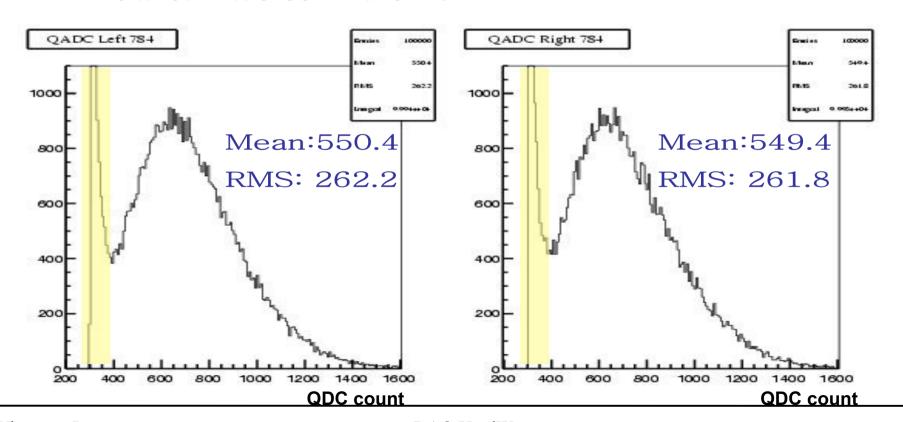


# QDC spectra

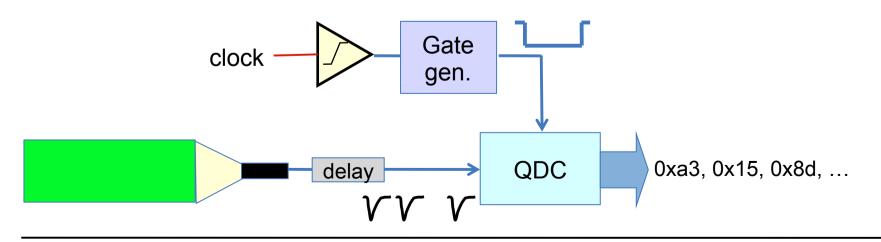
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- The pedestal can be measured with an out-of-phase trigger
  - PMT dark current, thermal noise, Jitter, fluctuations on power supply..
  - The same noise enters our physics measurements and contributes with an offset to the distribution
- The result of a pedestal measurement has to be subtracted from our charge measurements



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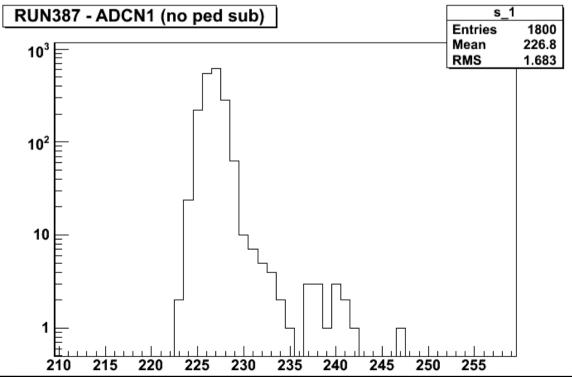
  We essentially want to integrate the baseline of our setup

clock Gate gen.

QDC 0xa3, 0x15, 0x8d, ...

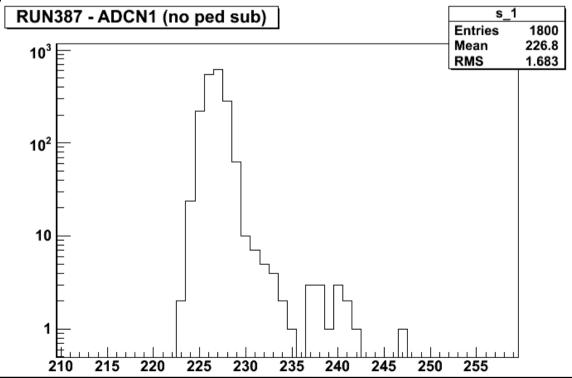
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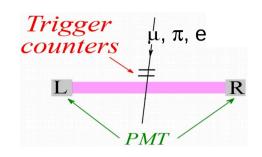


- The pedestal can be measured with an out-of-phase trigger
  - PMT dark current, thermal noise, Jitter, fluctuations on power supply..
  - The same noise enters our physics measurements and contributes with an offset to the distribution

• The result of a pedestal measurement has to be subtracted from our charge measurements

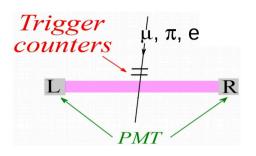


- PbWO<sub>4</sub> scintillating crystal equipped with two PMTs and exposed to e,  $\mu$  and  $\pi$  beams
  - Real data from a test beam @CERN





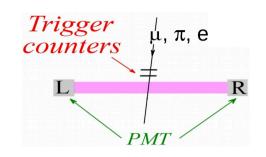
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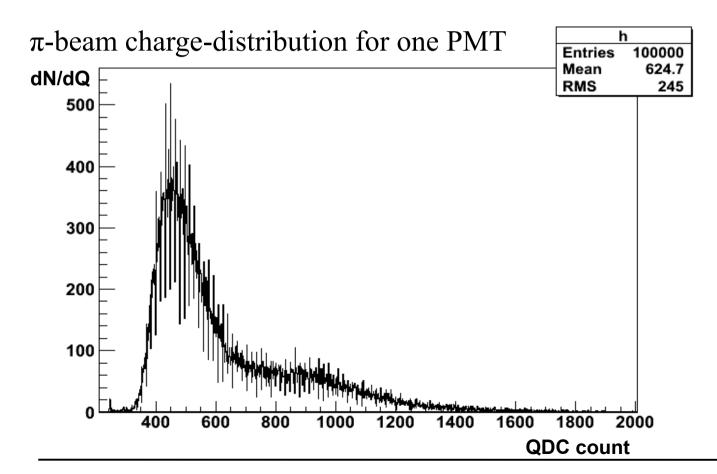


- A lot of effects will sum-up in a realistic case, like a test-beam
  - We can't feed our detector signal directly to the ADC (or QDC)
  - We have PMTs, transmission lines (with signal losses!), power supply fluctuations, impedance mismatches, reflections, distortions, etc..

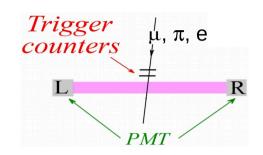


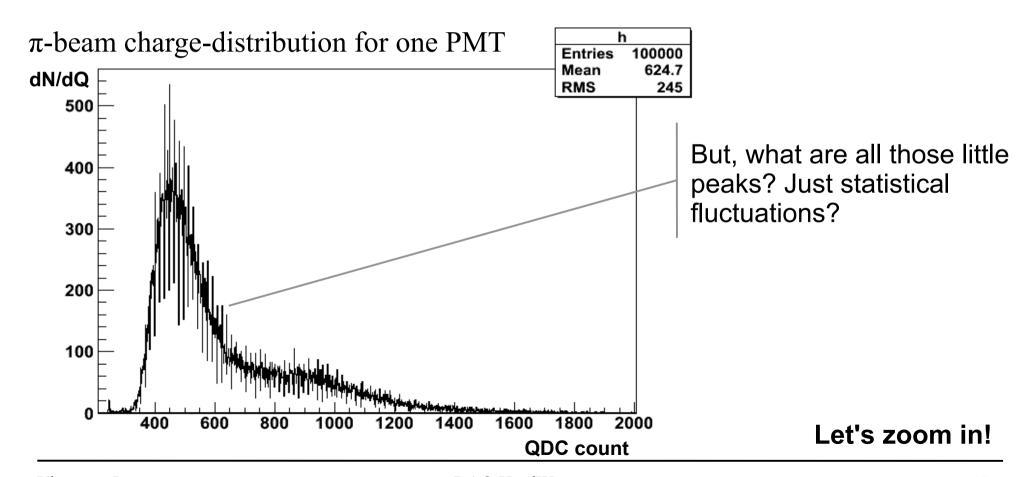
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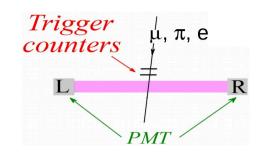


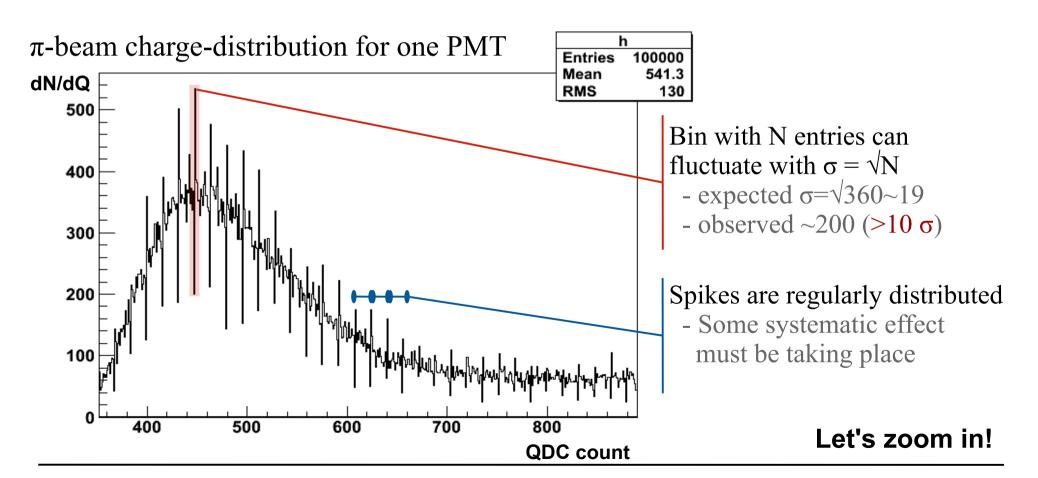
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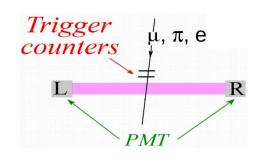


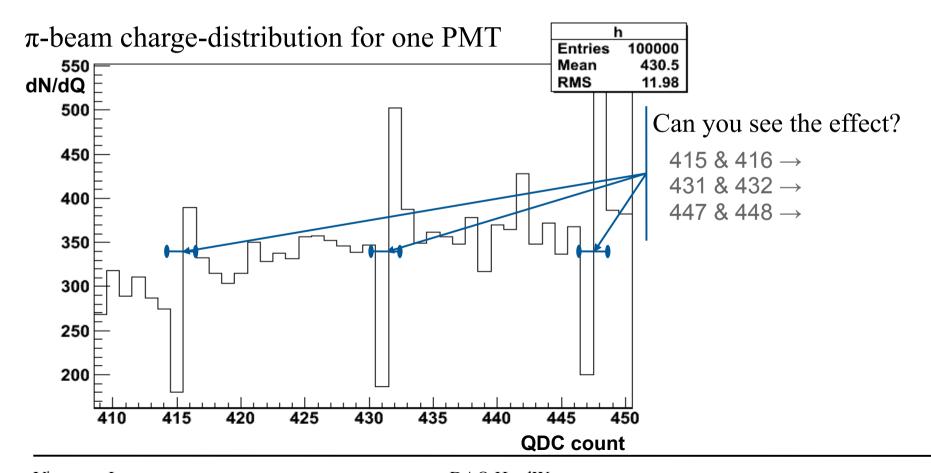
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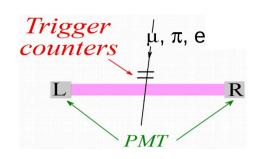


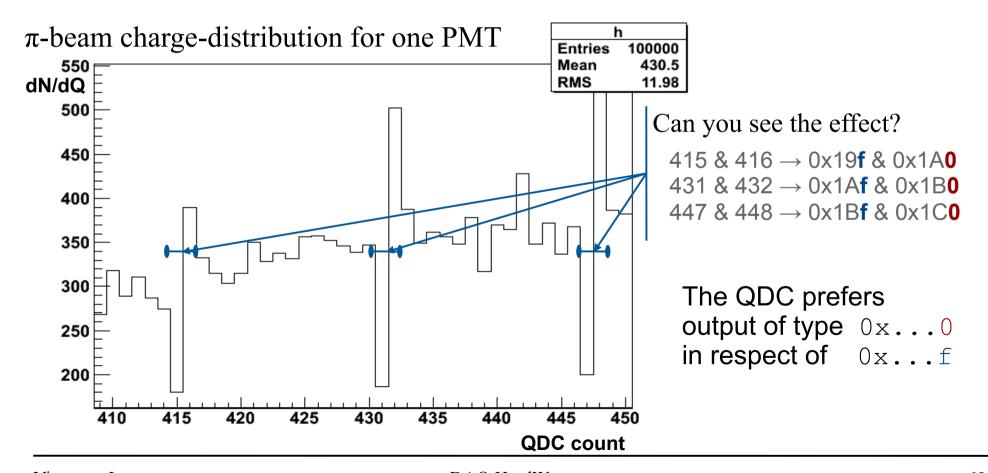
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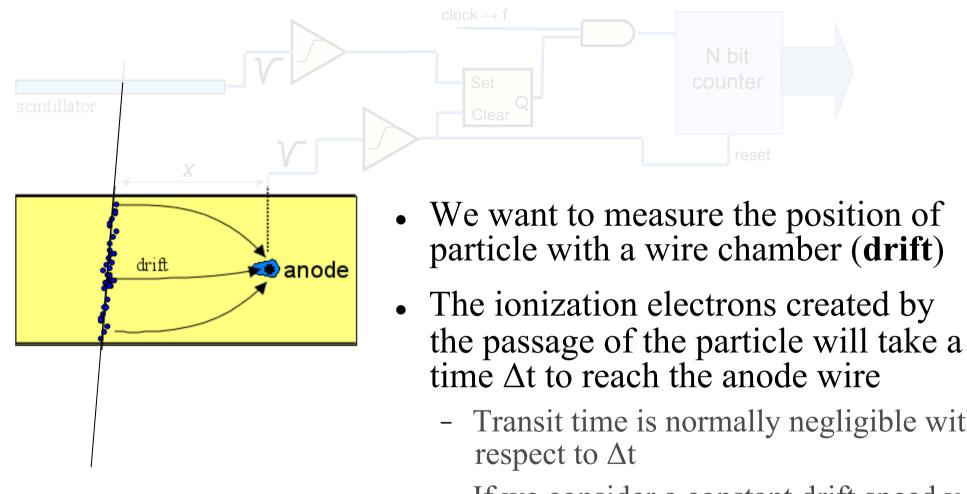


#### **Outline**

- Introduction
  - DAQ, Electronics & Readout Chain
- Measure energy deposition
  - Scintillator setup
  - Photomultiplier
  - Analog-to-Digital conversion
  - Charge-to-Digital conversion
  - QDC in real life
- Measure position
  - Wire chamber setup
  - Time-to-Digital conversion
  - TDC in real life
- Corollary



## **Position measurement**

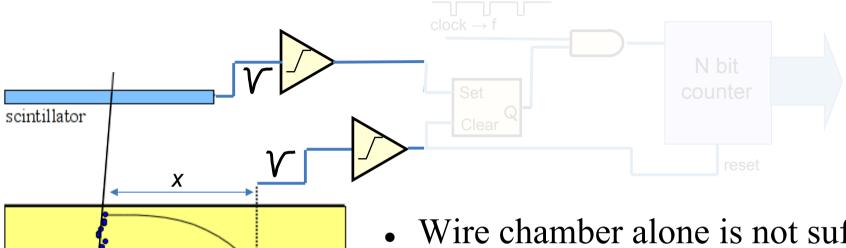


time  $\Delta t$  to reach the anode wire

- Transit time is normally negligible with
- If we consider a constant drift speed  $v_D$ (e.g.: 50  $\mu$ m/ns), then position is:

$$\mathbf{x} = \mathbf{v_D} \cdot \Delta \mathbf{t}$$

# **Triggering**



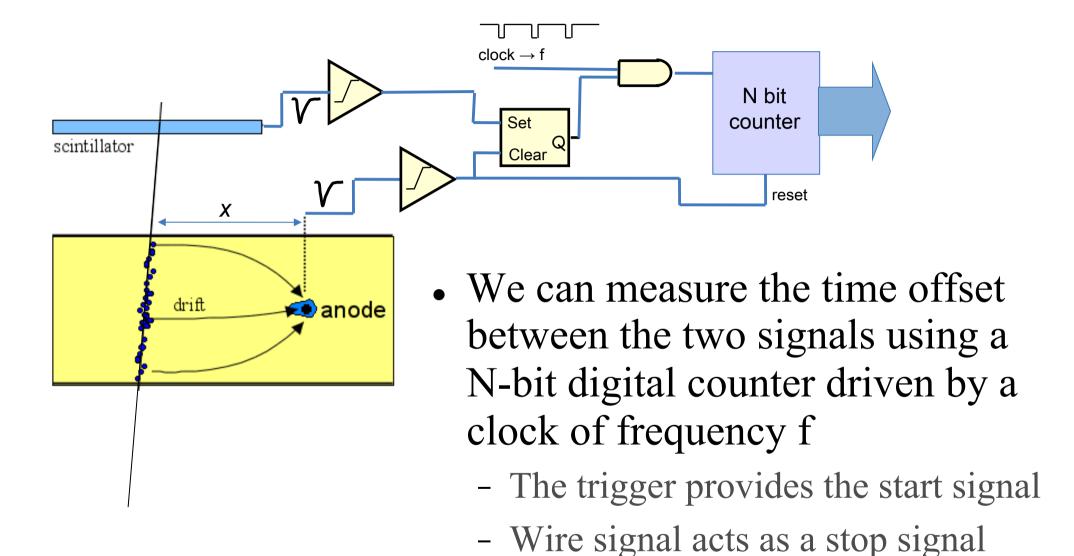
- Wire chamber alone is not sufficient
  - We need a triggering system
- We will measure a relative time
  - $t^* = \Delta t + t_0$
  - t<sub>0</sub> accounts for the time delays, offsets, ... between wire chamber and triggering system
- Assuming a constant drift

$$x = \alpha t^* + \beta$$

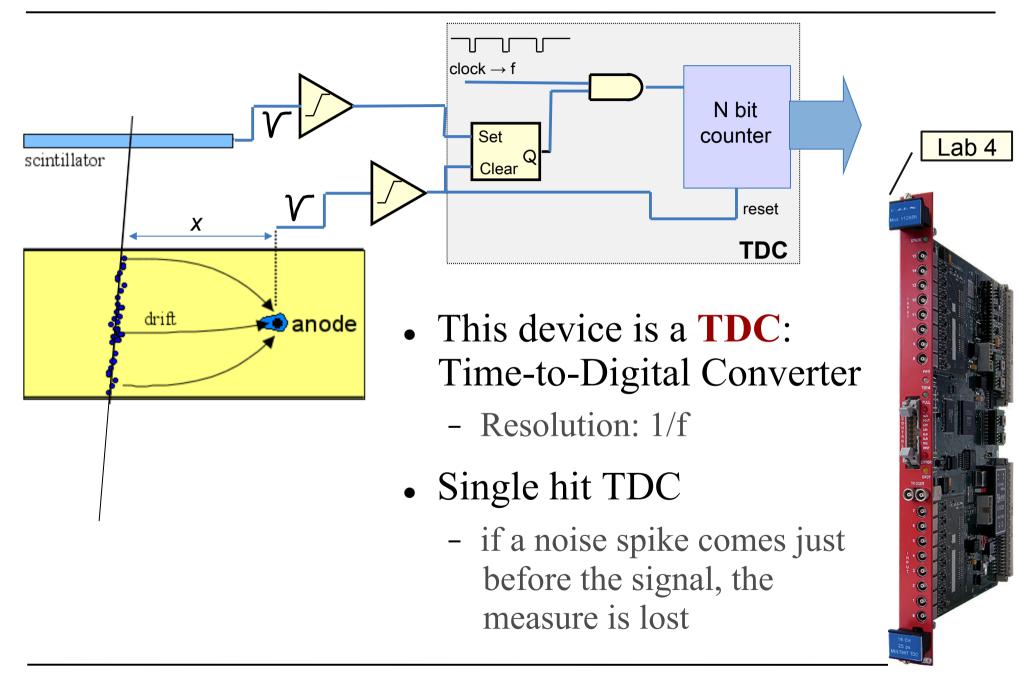
drift

🗪 anode

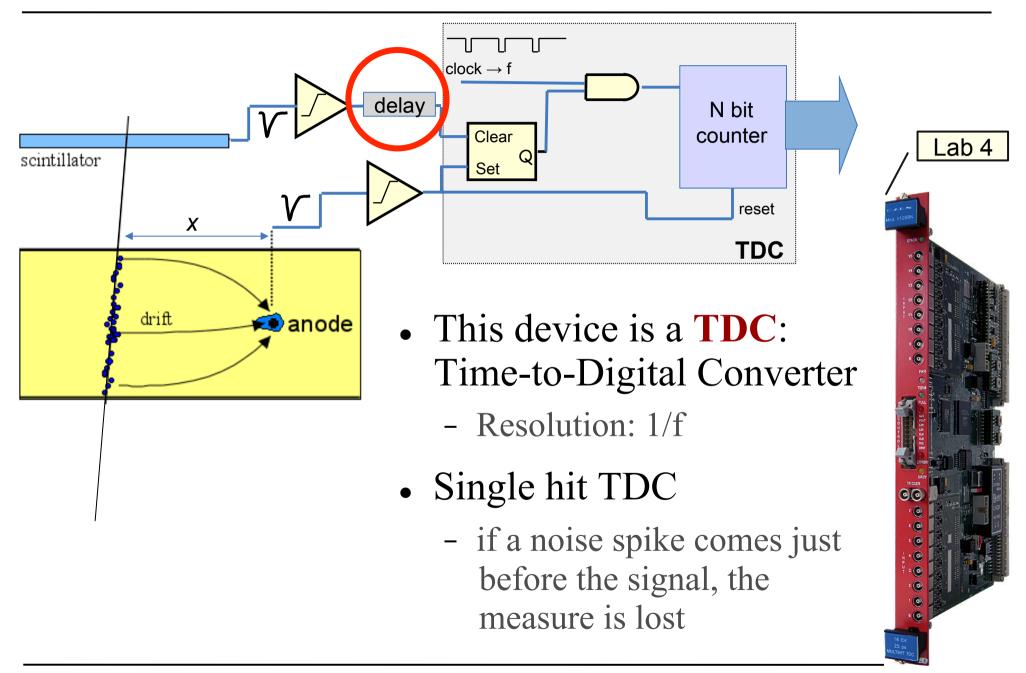
#### **Time measurement**



#### Time measurement: TDC

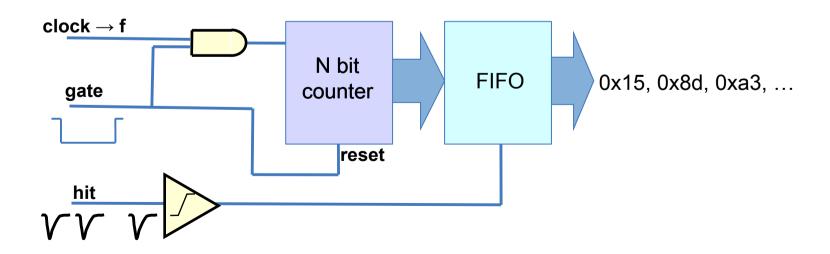


## Time measurement: TDC



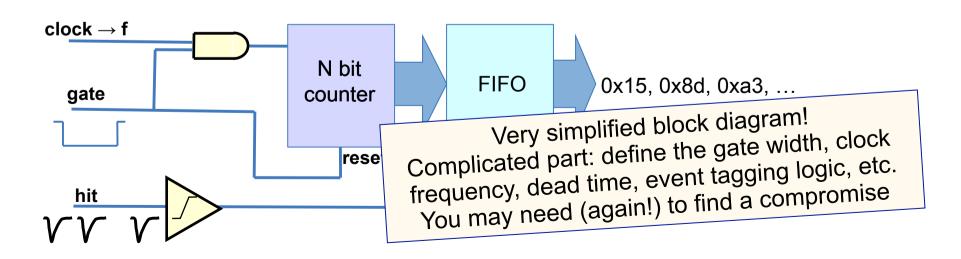
#### **Multi-hit TDC**

- Gate resets and starts the counter
  - It also provides the measurement period
- Each "hit" (i.e. signal) forces the FIFO to load the current value of the counter, that is the delay after the gate start
  - Common-start configuration
  - In order to distinguish between hits belonging to different gates, some additional logic is need to tag the data



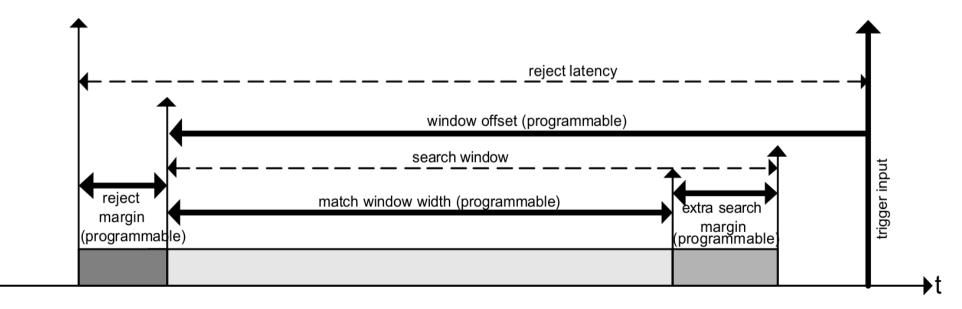
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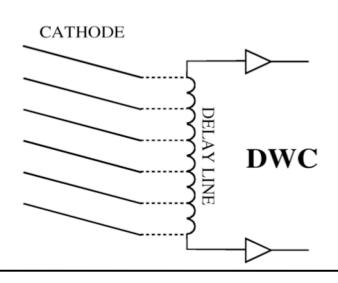
## **Actual TDCs**

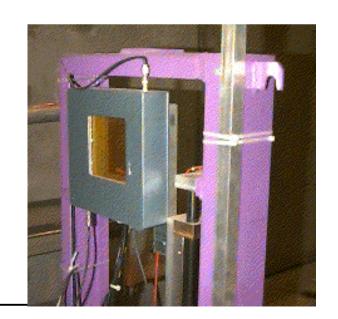
- Plenty of TDCs architectures available on the market
  - Common Start, Common Stop, Charging Capacitor, Vernier, etc.
- Real TDCs provide advanced functionalities for fine-tuning the hittrigger matching
  - Internal programmable delays or generation of programmable gates
  - Programmable rejection frames
  - Usually via a dedicated C library/API



## Real life wire chamber & TDC

- XDWC: delay wire chambers
  - used on the SPS extracted lines to measure beam profiles
- Two cathode planes provide X and Y positions
  - Measurement based on the delay gained along a delay line

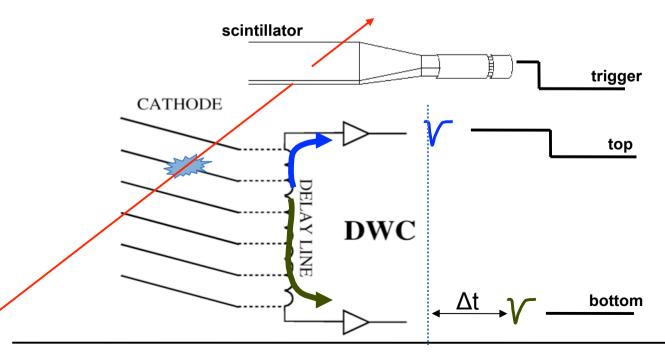


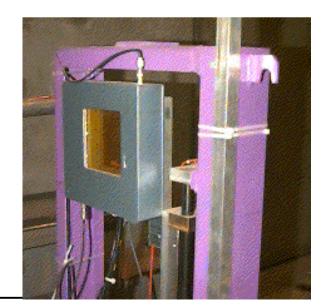


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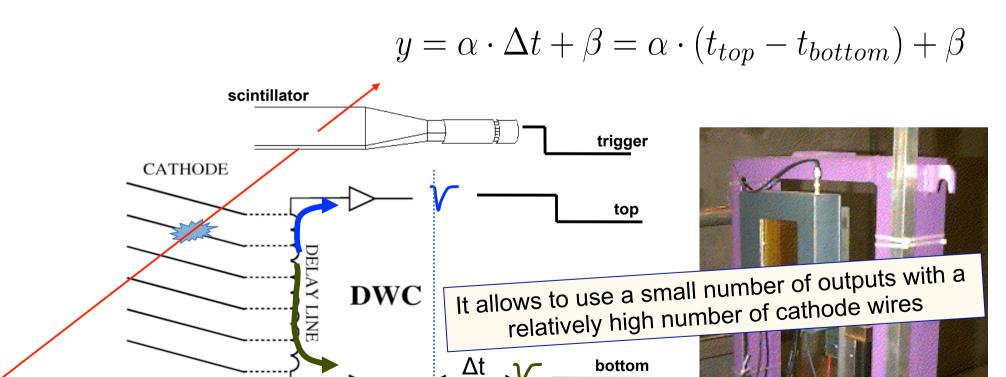
$$y = \alpha \cdot \Delta t + \beta = \alpha \cdot (t_{top} - t_{bottom}) + \beta$$





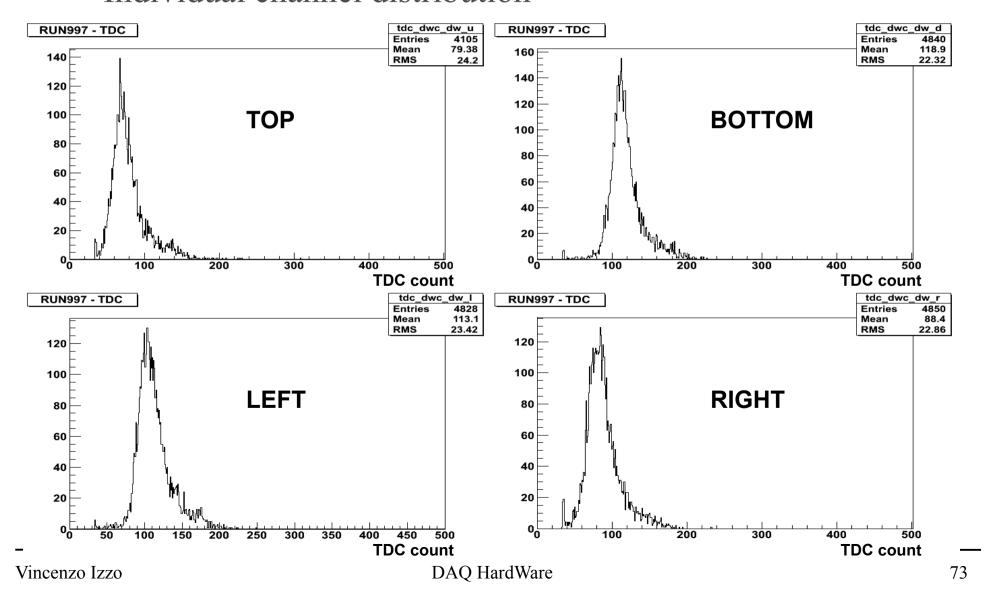
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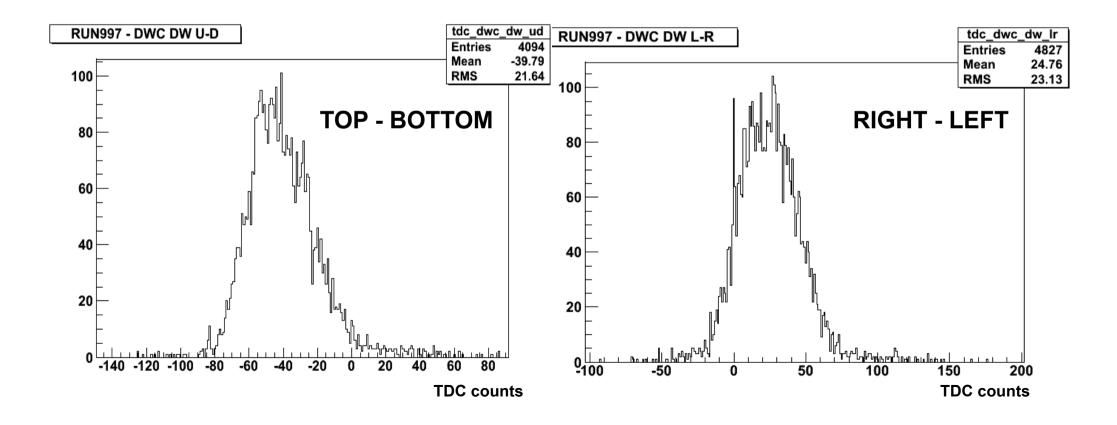
### Raw time data

- Take a run (some thousands events)
  - Individual channel distribution



### Un-calibrated beam profile

- Beam sizes are still in TDC counts
  - Not very useful, though
  - How do we convert this into a known scale (e.g. cm)?



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- Corollary: calibration



### **Calibration**

- Previous experiments provide relative measurements
  - Values obtained via our systems are in some (known) relation with the interesting quantities
    - Scintillator  $Q \propto N_{\gamma} \propto E$
    - XDWC  $y = \alpha \cdot \Delta t + \beta = \alpha \cdot (t_{top} t_{bottom}) + \beta$
- Our instruments need to be calibrated in order to give us the answer we are looking for
  - We have to determine the parameters that transform the raw data into a physics quantity
  - The parameters normally depend on the experimental setup (e.g. cable length, delay settings, HV settings, ...)
- NB: calibration mechanisms/procedures shall be foreseen in the design of our detector and DAQ

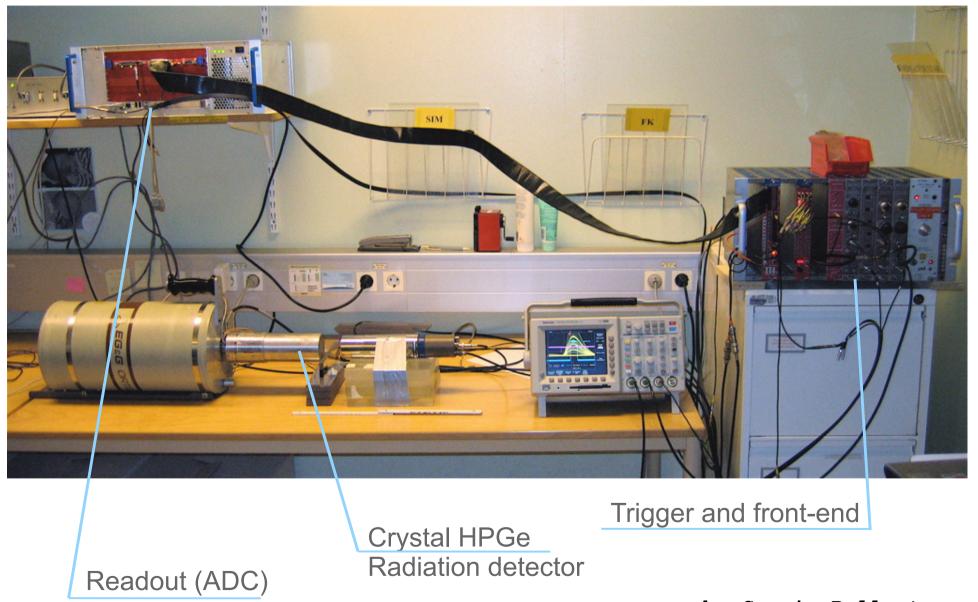
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- Our instruments the still don't know the proportionality However, we still don't know the proportionality factor between charge and energy, or between time and position
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## E.g.: Ge Crystal for isotope ID



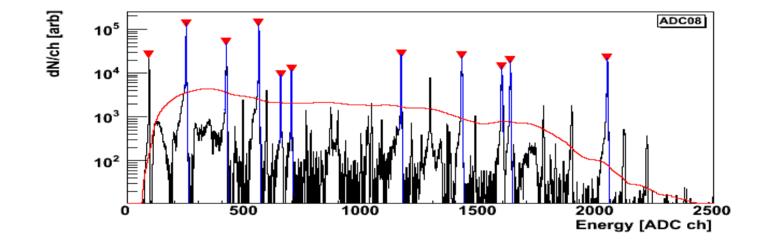
by Sergio Ballestrero

### Ge crystal calibration

- <sup>152</sup>Eu reference source allows for definition of the parameters describing functional relation between ADC count and E
  - Known γ emission lines

• Find the peaks and fit

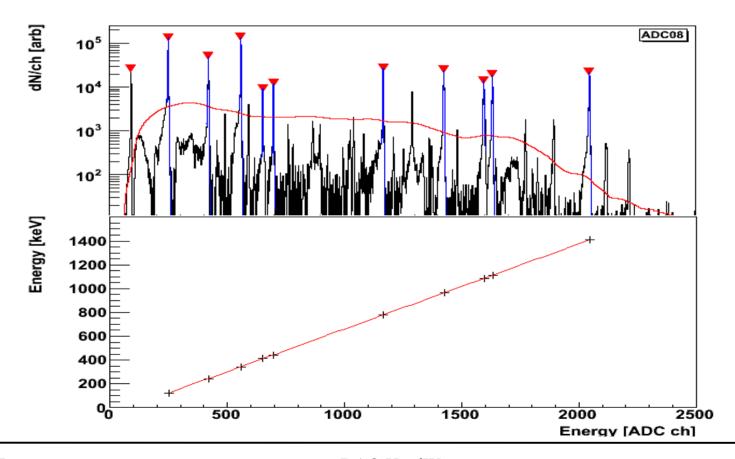
$$Q \propto N_{\gamma} \propto E$$



### Ge crystal calibration

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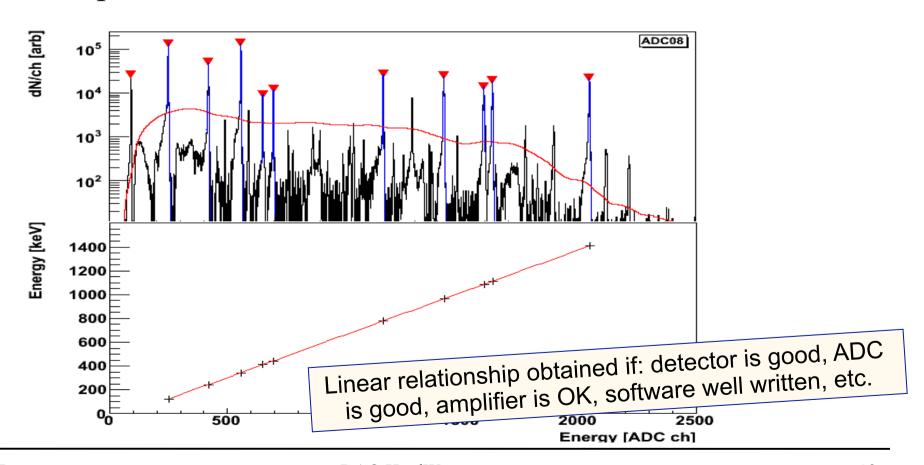
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# Ge crystal calibration

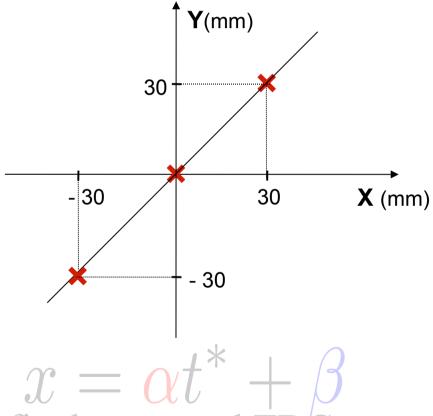
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### **Back to XDWC: calibration**

- XDWC chamber have 3 calibration inputs
  - allow for independent calibrations of X and Y axes with only 3 different sets of data
  - Calibration input simulate signals from particles respectively hitting
    - Right-top (X=Y=30mm)
    - Center (X=Y=0mm)
    - Left-bottom (X=Y=-30mm)
  - Interpolating the three points in t-x space, the parameters of the calibration equation can be measured

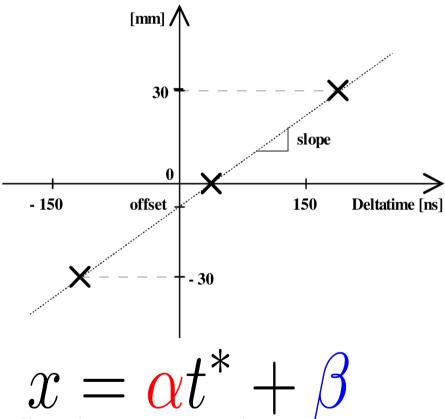


$$x = \alpha t^* + \beta$$

Calibration shall be done with final setup and TD

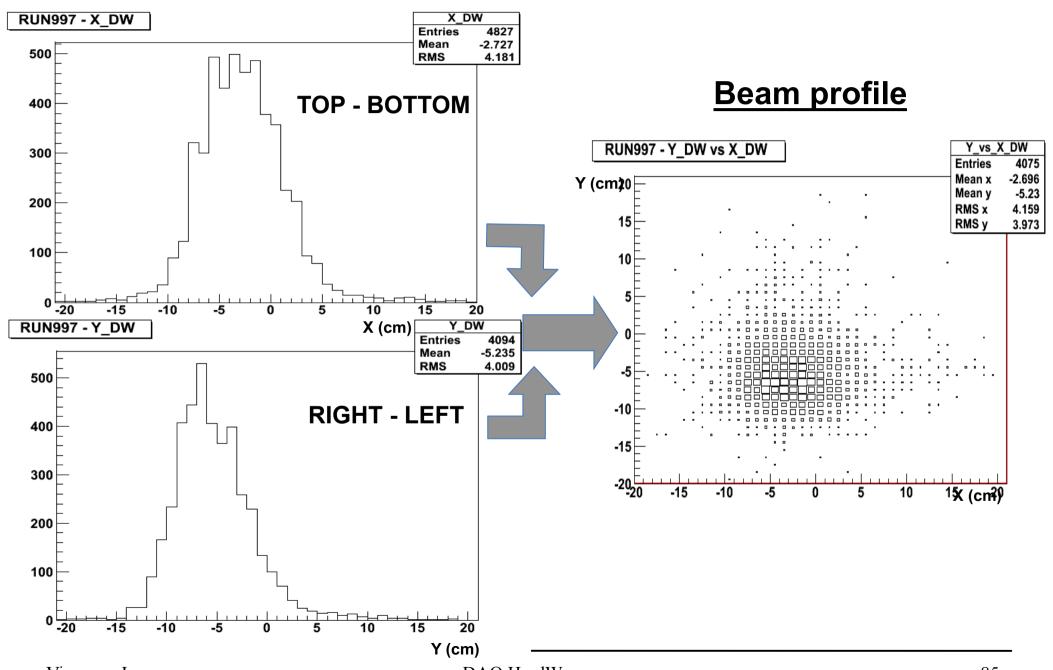
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• Calibration shall be done with final setup and TDC

#### **Calibrated XDWC**



### Wrap-up

- Digitization techniques produce data directly manageable by digital systems (e.g. a computer)
  - Greatly simplifies the down-stream data-handling
  - Available on a variety of platforms: VME, ATCA, PCI, USB, ...
  - Root of every modern DAQ system
- Frequently you have to open the "black box" and see where numbers come from
  - Real electronics does not behave as the ideal one



- Trade-offs between speed/precision/cost exist
  - You have to choose the solution that best suits you
- Physics quantities are derived from raw data via calibration
  - Calibration procedures to be foreseen for your detector/DAQ

# Thank you!